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A comprehensive overview of X-ray scattering using nano-focused beams for probing matter at the nanoscale is presented. The monograph includes guidance on the design of nano-beam experiments and discusses various sources, including free electron lasers, synchrotron radiation and special laboratory sources.

The rapid progress of this research area was initiated by the availability of brilliant well-collimated synchrotron X-ray sources and is strongly linked to the recent development of state-of-the art devices now capable to focus hard X-rays. Accordingly, several experimental methods have developed, such as nano-beam based scanning diffraction microscopy and spectroscopy, coherent diffraction imaging, etc. They are used in a broad range of applications in material science, from semiconductor nanostructures to biological specimen.

It therefore seems a good time to give a first résumé on the achievements made, an overview on techniques and applications currently available, and based on that, an outlook on the potential of this approach.

From the contents:

- · X-ray diffraction principles
- X-ray focusing elements characterization
- Nanobeam diffraction
- Nanobeam diffraction setups
- · Spectroscopic techniques using focused beams
- Coherent diffraction
- Coherent limits
- Future developments



Julian Stangl is working on the investigation of semiconductor nanostructures using x-ray scattering at Johannes Kepler University in Linz, Austria. He has been developing nanobeam diffraction in collaboration with the European Synchrotron radiation facility in Grenoble, France. He received several scientific awards, including the Erich Schmid price of the Austrian Academy of Sciences.



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Virginie Chamard is a researcher at CNRS, located in the Fresnel Institute in Marseille, France. Her research activity concerns the developments of x-ray lens-less microscopy techniques, with the aim of imaging nano-structured crystal. She developed several original approaches for mapping strain at the nanoscale, based on the inversion of coherent intensity patterns.



Dina Carbone works on the exploitation of small (coherent) x-ray beams for the investigation of strain in complex materials, and its effect on their physical properties and functionality. As beamline scientist at the European Synchrotron Radiation Facility in Grenoble, France, she is also contributing to the technical and methodological developments of nano-beam diffraction.

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